


<b>Search Notes</b> 	<b>Application/Control No.</b> 10692314	<b>Applicant(s)/Patent Under Reexamination</b> KRANZ ET AL.
	<b>Examiner</b> Pardo, Thuy N	<b>Art Unit</b> 2168

### SEARCHED

Class	Subclass	Date	Examiner
707	2, 3, 6, 10	3/16/2007	TP
705	59	3/16/2007	TP
709	229	3/16/2007	TP
713	153, 189	3/16/2007	TP
707	102	12/6/2007	TP
705	57	12/6/2007	TP
713	165, 189	12/6/2007	TP
726	32	12/6/2007	TP
705	51, 59	5/25/2008	TP
713	189, 193	5/25/2008	TP
707	6, 101, 102, 103X, 104.1	11/21/2008	TP
705	57	11/21/2008	TP

### SEARCH NOTES

Search Notes	Date	Examiner
WEST	3/16/2007	TP
WEST	12/6/2007	TP
WEST, NPL (IEEE, ACM)	5/25/2008	TP
WEST, NPL (ACM)	11/21/2008	TP

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
707	2, 3, 6, 9, 10, 101, 102, 103X, 104.1	11/21/2008	TP
705	51, 57, 59	11/21/2008	TP
709	229	11/21/2008	TP
713	165, 189	11/21/2008	TP
726	32	11/21/2008	TP

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